

## EAST Search History

| Ref # | Hits   | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|--------|--|---|------------------|---------|------------------|
| S5    | 67018  | electrical adj characteristic  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:17 |
| S6    | 79540  | pattern same wafer   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:18 |
| S7    | 113525 | (initial first) with design  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:19 |
| S8    | 29556  | layout same generat\$3   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:19 |
| S9    | 30     | S5 and S6 and S7 and S8  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:20 |
| S10   | 22     | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:28 |
| S11   | 21     | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:28 |
| S12   | 20     | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/04/13 19:29 |

## EAST Search History

|     |    |  |   |    |    |                  |
|-----|----|--|---|----|----|------------------|
| S13 | 20 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion                                     | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/13 19:29 |
| S14 | 20 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion and size                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/13 19:30 |
| S15 | 17 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion and size and adjacent               | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/13 19:33 |
| S16 | 0  | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion and size and adjacent and intensity | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/13 19:33 |
| S17 | 16 | layout adj generat\$3 and modif\$7 with design and electrical adj characteristic   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 13:28 |
| S18 | 6  | layout adj generat\$3 and modif\$7 with design same electrical adj characteristic  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 13:28 |
| S19 | 1  | ( actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:29 |
| S20 | 0  | ( actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design) and layout with generat\$3              | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:28 |

## EAST Search History

|     |        |   |   |    |    |                  |
|-----|--------|---|---|----|----|------------------|
| S21 | 0      | ( actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design) and layout same generat\$3             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:29 |
| S22 | 0      | ( actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design) and ( physical layout) same generat\$3 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:29 |
| S23 | 14540  | layout with generat\$3  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:30 |
| S24 | 67018  | electrical adj characteristic   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:30 |
| S25 | 3088   | simulat\$3 same structure same pattern  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:31 |
| S26 | 169262 | (actual desired) same (design characteristic)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:32 |
| S27 | 17024  | (actual desired) same (design characteristic) same modif\$7   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:33 |
| S28 | 9      | S23 and S24 and S25 and S27   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:44 |

## EAST Search History

|     |     |  |   |    |    |                  |
|-----|-----|--|---|----|----|------------------|
| S29 | 190 | slope near4 edge with intensity                          | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:47 |
| S30 | 0   | S28 and S29  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:47 |
| S31 | 22  | process adj2 variation same slope and layout             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:50 |
| S32 | 0   | S31 and S28  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:48 |
| S33 | 20  | process adj2 variation same slope and layout and feature | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:58 |
| S34 | 3   | S23 and S33  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:53 |
| S35 | 1   | S23 and S33 and S24                                      | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:53 |
| S36 | 9   | S33 and S24  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 14:55 |

## EAST Search History

|     |       |   |   |    |    |                  |
|-----|-------|---|---|----|----|------------------|
| S37 | 344   | slope with (edge intensity) same (larger smaller ) same variation                                 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 15:00 |
| S38 | 0     | S37 and S23 and S24   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/14 15:02 |
| S43 | 67024 | electrical adj characteristic   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:01 |
| S44 | 8021  | electrical adj characteristic and model\$3  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:01 |
| S45 | 60    | electrical adj characteristic same layout same simulat\$3   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:02 |
| S46 | 37    | electrical adj characteristic same layout same simulat\$3 and pattern                             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:02 |
| S47 | 27    | electrical adj characteristic same layout same simulat\$3 and pattern and variation               | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:03 |
| S48 | 26    | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:03 |

## EAST Search History

|     |      |   |   |    |    |                  |
|-----|------|---|---|----|----|------------------|
| S49 | 20   | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:03 |
| S50 | 17   | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:03 |
| S51 | 17   | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:04 |
| S52 | 13   | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5 with layout | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:10 |
| S53 | 56   | electrical adj characteristic and layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5 with layout  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:14 |
| S54 | 63   | electrical adj characteristic and layout and simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5 with layout   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:27 |
| S55 | 1342 | intensity same edge same slope  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:29 |
| S56 | 0    | S54 and S55   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:28 |

## EAST Search History

|     |      |  |   |    |    |                  |
|-----|------|--|---|----|----|------------------|
| S57 | 1797 | intensity same edge same<br>(derivative slope)             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:29 |
| S58 | 0    | S54 and S57  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:29 |
| S59 | 1895 | intensity same edge same<br>(derivative slope logarith\$2) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:30 |
| S60 | 0    | S54 and S59  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:39 |
| S61 | 1226 | 716/2.ccls.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:39 |
| S62 | 47   | 716/2.ccls. and variation and S43                          | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:52 |
| S63 | 8    | 716/2.ccls. and variation and S43<br>and pattern and wafer | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:40 |
| S64 | 7    | layout adj simulation adj tool                             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:53 |

## EAST Search History

|     |     |   |   |    |    |                  |
|-----|-----|---|---|----|----|------------------|
| S65 | 5   | layout adj simulation adj tool and electrical adj characteristic  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:54 |
| S66 | 2   | layout adj simulation adj tool and electrical adj characteristic and variation  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:55 |
| S67 | 486 | layout and simulat\$3 and electrical adj characteristic and variation and pattern   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:55 |
| S68 | 212 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:55 |
| S69 | 58  | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:56 |
| S70 | 58  | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure                             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:56 |
| S71 | 58  | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3              | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:56 |
| S72 | 57  | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:58 |



## EAST Search History

|     |     |  |   |    |    |                  |
|-----|-----|--|---|----|----|------------------|
| S73 | 0   | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 and netlist                          | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:57 |
| S74 | 0   | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 and (HDL netlist)                    | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:57 |
| S75 | 4   | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 and wafer                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 10:58 |
| S76 | 13  | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and (derivative slope) and structure and generat\$3 and modif\$5 and wafer               | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 11:03 |
| S77 | 7   | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and (derivative slope) same position and structure and generat\$3 and modif\$5 and wafer | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 11:03 |
| S78 | 960 | (slope derivative) same (larger small greater less more) same edge same intensity  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 13:39 |
| S79 | 27  | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 13:42 |
| S80 | 20  | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 13:42 |

## EAST Search History

|     |    |  |   |    |    |                  |
|-----|----|--|---|----|----|------------------|
| S81 | 20 | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation and process                                   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 13:45 |
| S82 | 2  | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation and process and electrical adj characteristic | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/04/16 13:43 |